

EMC OPTIMIZED CAN TRANSCEIVER

FEATURES

- Improved Replacement for the TJA1050
- High Electromagnetic Immunity (EMI)
- Very Low Electromagnetic Emissions (EME)
- Meets or Exceeds the Requirements of ISO 11898-2
- Bus-Fault Protection of –27 V to 40 V
- Dominant Time-Out Function
- Thermal Shutdown Protection
- Power-Up/Down Glitch-Free Bus Inputs and Outputs
 - High Input Impedance with Low V_{CC}
 - Monotonic Outputs During Power Cycling

APPLICATIONS

- Industrial Automation
 - DeviceNet™ Data Buses (Vendor ID #806)
- SAE J2284 High Speed CAN for Automotive Applications
- SAE J1939 Standard Data Bus Interface
- ISO 11783 Standard Data Bus Interface
- NMEA 2000 Standard Data Bus Interface

DESCRIPTION

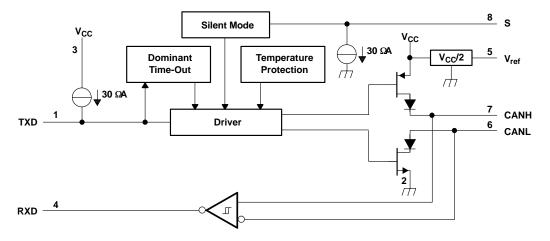
The SN65HVD1050 meets or exceeds the specifications of the ISO 11898 standard for use in applications employing a Controller Area Network (CAN). The device is also qualified for use in automotive applications in accordance with AEC-Q100.⁽¹⁾

As a CAN transceiver, this device provides differential transmit capability to the bus and differential receive capability to a CAN controller at signaling rates up to 1 megabit per second (Mbps)⁽²⁾.

Designed for operation is especially harsh environments, the HVD1050 features cross-wire, over-voltage and loss of ground protection from -27 V to 40V, over-temperature protection, a -12 V to 12 V common-mode range, and will withstand voltage transients from -200 V to 200 V according to ISO 7637.

- The device is available with Q100 qualification as the SN65HVD1050Q (PRODUCT PREVIEW).
- (2) The signaling rate of a line is the number of voltage transitions that are made per second expressed in the units bps (bits per second).

FUNCTION BLOCK DIAGRAM



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

DESCRIPTION (CONTINUED)

Pin 8 provides for two different modes of operation: high-speed or silent mode. The high-speed mode of operation is selected by connecting S (pin 8) to ground.

If a high logic level is applied to the S pin of the SN65HVD1050, the device enters a listen-only silent mode during which the driver is switched off while the receiver remains fully functional.

In silent mode, all bus activity is passed by the receiver output to the local protocol controller. When data transmission is required, the local protocol controller reverses this low-current silent mode by placing a logic-low on the S pin to resume full operation.

A dominant-time-out circuit in the SN65HVD1050 prevents the driver from blocking network communication with a hardware or software failure. The time-out circuit is triggered by a falling edge on TXD (pin 1). If no rising edge is seen before the time-out constant of the circuit expires, the driver is disabled. The circuit is then reset by the next rising edge on TXD.

 V_{ref} (pin 5) is available as a $V_{CC}/2$ voltage reference.

The SN65HVD1050 is characterized for operation from -40°C to 125°C.

ORDERING INFORMATION

PART NUMBER	PACKAGE	MARKED AS	ORDERING NUMBER
SN65HVD1050	65HVD1050 SOIC-8 VP1050		SN65HVD1050D (rail)
SNOSHVD1030	3010-0	VP1030	SN65HVD1050DR (reel)

ABSOLUTE MAXIMUM RATINGS(1)

		UNIT
V_{CC}	Supply voltage ⁽²⁾	–0.3 V to 7 V
	Voltage range at any bus terminal (CANH, CANL, V _{ref})	–27 V to 40 V
Io	Receiver output current	20 mA
VI	Voltage input, transient pulse (3) (CANH, CANL)	-200 V to 200 V
VI	Voltage input range (TXD, S)	-0.5 V to 6 V
T_{J}	Junction temperature	−40°C to 170°C

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

⁽²⁾ All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.

⁽³⁾ Tested in accordance with ISO 7637, test pulses 1, 2, 3a, 3b, 5, 6, and 7.



ELECTROSTATIC DISCHARGE PROTECTION

over operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		UNIT
	Lluman Dady Madal(2)	Bus terminals and GND	±8 kV
	Human Body Model (2)	All pins	±4 kV
Electrostatic discharge (1)	Charged Device Model (3)	All pins	±1.5 kV
	Machine Model		±0.2 V

- All typical values at 25°C.
- (2) Tested in accordance JEDEC Standard 22, Test Method A114-A.
- (3) Tested in accordance JEDEC Standard 22, Test Method C101.

RECOMMENDED OPERATING CONDITIONS

			MIN	NOM N	IAX	UNIT
V_{CC}	Supply voltage		4.75	5	5.25	V
V _I or V _{IC}	Voltage at any bus terminal (separately or common mode)	-12		12	V
V _{IH}	High-level input voltage	TVD C	2	5	5.25	V
V _{IL}	Low-level input voltage	TXD, S	0		8.0	V
V _{ID}	Differential input voltage	Differential input voltage			7	V
	High lavel autout august	Driver	-70			A
Іон	High-level output current	Receiver	-2			mA
	Laurian autorit arimont	Driver			70	A
IOL	Low-level output current	Receiver			2	mA
TJ	Junction temperature	See Thermal Characteristics table, 1 Mbps minimum signaling rate with R_L = 54Ω			150	°C

SUPPLY CURRENT

over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
		Silent mode	S at V_{CC} , $V_I = V_{CC}$		6	10	
Icc	5-V Supply current	Dominant	$V_I = 0 \text{ V}$, 60 Ω Load, S at 0 V		50	70	mA
		Recessive	V _I = V _{CC} , No Load, S at 0 V		6	10	

DEVICE SWITCHING CHARACTERISTICS

over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP MAX	UNIT
t _{d(LOOP1)}	Total loop delay, driver input to receiver output, recessive to dominant	Figure 0. S at 0V	90	190	20
t _{d(LOOP2)}	Total loop delay, driver input to receiver output, dominant to recessive	Figure 9, S at 0V	90	190	ns

DRIVER ELECTRICAL CHARACTERISTICS

over recommended operating conditiions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
Variable Rus output voltage (Dominant) CANH	$V_I = 0 \text{ V}$, S at 0 V, $R_L = 60 \Omega$, See Figure 1	2.9	3.4	4.5	\ \ \ \		
v O(D)	V _{O(D)} Bus output voltage (Dominant) CANL		and Figure 2	0.8		1.5	v
V _{O(R)}	Bus output voltage (Recessive)		V_I = 3 V, S at 0 V, R_L = 60 Ω , See Figure 1 and Figure 2	2	2.3	3	V

⁽¹⁾ All typical values are at 25°C with a 5-V supply.



DRIVER ELECTRICAL CHARACTERISTICS (continued)

over recommended operating conditiions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT	
M	Differential output voltage (Dominant)	V_I = 0 V, R_L = 60 Ω , S at 0 V, See Figure 1, Figure 2, and Figure 3	1.5		3	V	
$V_{OD(D)}$	Dinerential output voltage (Dominant)	V_I = 0 V, R_L = 45 Ω , S at 0 V, See Figure 1, Figure 2, and Figure 3	1.4		3	V	
V	Differential output valtage (Peccesive)	V _I = 3 V, S at 0 V, See Figure 1 and Figure 2	-0.012		0.012	V	
$V_{OD(R)}$	Differential output voltage (Recessive)	V _I = 3 V, S at 0 V, No Load	-0.5		0.05	V	
V _{OC(ss)}	Steady state common-mode output voltage	C at 0 \/ Figure 0	2	2.3	3	V	
$\Delta V_{OC(ss)}$	Change in steady-state common-mode output voltage	S at 0 V, Figure 8		30		mV	
I _{IH}	High-level input current, TXD input	V _I at V _{CC}	-2		2		
I _{IL}	Low-level input current, TXD input	V _I at 0 V	-50		-10	μΑ	
I _{O(off)}	Power-off TXD output current	V _{CC} at 0 V, TXD at 5 V			1		
		V _{CANH} = -12 V, CANL Open, See Figure 11	-105	-72			
	Chart sine it stands state autout surrout	V _{CANH} = 12 V, CANL Open, SeeFigure 11		0.36	1	A	
I _{OS(ss)}	Short-circuit steady-state output current	V _{CANL} = -12 V, CANH Open, See Figure 11	-1	-0.5		mA	
		V _{CANL} = 12 V, CANH Open, See Figure 11		71	105		
Co	Output capacitance	See receiver input capacitance					

DRIVER SWITCHING CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH}	Propagation delay time, low-to-high-level output		25	65	120	
t _{PHL}	Propagation delay time, high-to-low-level output	S at 0 V, See Figure 4	25	45	90	
t _r	Differential output signal rise time			25		ns
t _f	Differential output signal fall time			50		
t _{en}	Enable time from silent mode to dominant	See Figure 7			1	μs
t _(dom)	Dominant time-out	↓V _I , See Figure 10	300	450	700	μs

RECEIVER ELECTRICAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
V _{IT+}	Positive-going input threshold voltage	S at 0 V, See Table 1		800	900	
V _{IT} _	Negative-going input threshold voltage	S at 0 v, See Table 1	500	650		mV
V_{hys}	Hysteresis voltage (V _{IT+} - V _{IT-})		100	125		
V_{OH}	High-level output voltage	I _O = −2 mA, See Figure 6	4	4.6		V
V _{OL}	Low-level output voltage	I _O = 2 mA, See Figure 6		0.2	0.4	V
I _{I(off)}	Power-off bus input current	CANH or CANL = 5 V, Other pin at 0 V, V _{CC} at 0 V, TXD at 0 V		165	250	μA
I _{O(off)}	Power-off RXD leakage current	V _{CC} at 0 V, RXD at 5 V			20	μΑ
C _I	Input capacitance to ground, (CANH or CANL)	TXD at 3 V, V _I = 0.4 sin (4E6πt) + 2.5 V		13		pF
C _{ID}	Differential input capacitance	TXD at 3 V, $V_1 = 0.4 \sin (4E6\pi t)$		5		•
R _{ID}	Differential input resistance	TXD at 3 V, S at 0 V	30		80	kΩ
R _{IN}	Input resistance, (CANH or CANL)	- 1 A D at 3 V, 3 at 0 V	15	30	40	K77

(1) All typical values are at 25°C with a 5-V supply.

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RECEIVER ELECTRICAL CHARACTERISTICS (continued)

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
R _{I(m)}	Input resistance matching [1 – (R _{IN (CANH)} / R _{IN (CANL)})] x 100%	$V_{(CANH)} = V_{(CANL)}$	-3%	0%	3%	

RECEIVER SWITCHING CHARACTERISTICS

over recommended operating conditiions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{PLH}	Propagation delay time, low-to-high-level output	S at 0 V at V Saa Figure 6	60	100	130	ns
t _{PHL}	Propagation delay time, high-to-low-level output	S at 0 V at V San Figure 6	45	70	90	ns
t _r	Output signal rise time	S at 0 V or V _{CC} , See Figure 6	60 100 130	ns		
t _f	Output signal fall time			8		ns

S-PIN CHARACTERISTICS

over recommended operating conditiions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
I _{IH}	High level input current	S at 2 V	20	40	70	
I _{IL}	Low level input current	S at 0.8 V	5	20	30	μΑ

VREF-PIN CHARACTERISTICS

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
Vo	Reference output voltage	–50 μA < I _O < 50 μA	0.4 V _{CC}	0.5 V _{CC}	0.6 V _{CC}	V

THERMAL CHARACTERISTICS

over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN TYP	MAX	UNIT
0	Junction-to-Air	Low-K thermal resistance ⁽¹⁾			
θ_{JA}	Junction-to-All	High-K thermal resistance	131		
θ_{JB}	Junction-to-Board Thermal Resistance		53		°C/W
$\theta_{\sf JC}$	Junction-to-Case Thermal Resistance		79		
1	A	V_{CC} = 5.0 V, T_{j} = 27°C, R_{L} = 60 Ω , S at 0 V, Input to TXD a 500 kHz, 50% duty cycle square wave. CL at RXD = 15 pF	112		mW
P _D	Average power dissipation	V_{CC} = 5.5 V, T_j = 130°C, R_L = 45 $\Omega,$ S at 0 V, Input to TXD a 500 kHz, 50% duty cycle square wave. CL at RXD = 15 pF		170	
	Thermal shutdown temperature		190		°C

⁽¹⁾ Tested in accordance with the Low-K or High-K thermal metric definitions of EIA/JESD51-3 for leaded surface-mount packages.

FUNCTION TABLES

DRIVER

INP	UTS	OUTP	BUS STATE	
TXD ⁽¹⁾	S ⁽¹⁾	CANH ⁽¹⁾	CANL ⁽¹⁾	
L	L or Open	Н	L	DOMINANT
Н	X	Z	Z	RECESSIVE
Open	X	Z	Z	RECESSIVE
Х	Н	Z	Z	RECESSIVE

(1) H = high level; L = low level; X = irrelevant; ? = indeterminate; Z = high impedance

RECEIVER

DIFFERENTIAL INPUTS V _{ID} = V(CANH) - V(CANL)	OUTPUT RXD ⁽¹⁾	BUS STATE
V _{ID} ≥ 0.9 V	L	DOMINANT
0.5 V < V _{ID} < 0.9 V	?	?
V _{ID} ≤ 0.5 V	Н	RECESSIVE
Open	Н	RECESSIVE

(1) H = high level; L = low level; X = irrelevant; ? = indeterminate; Z = high impedance

PARAMETER MEASUREMENT INFORMATION

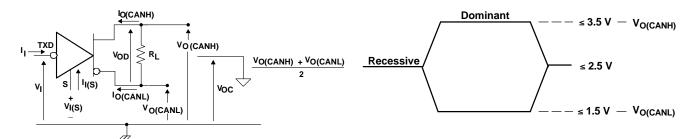


Figure 1. Driver Voltage, Current, and Test Definition

Figure 2. Bus Logic State Voltage Definitions

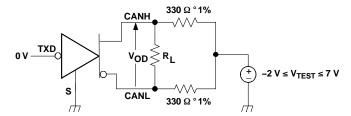


Figure 3. Driver V_{OD} Test Circuit



PARAMETER MEASUREMENT INFORMATION (continued)

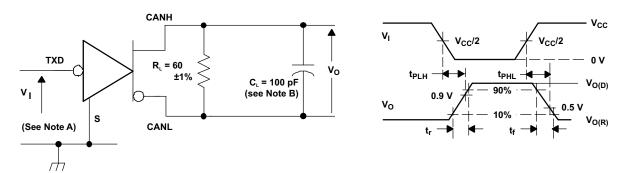


Figure 4. Driver Test Circuit and Voltage Waveforms

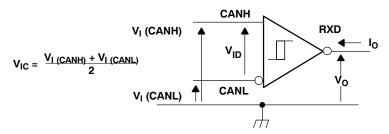
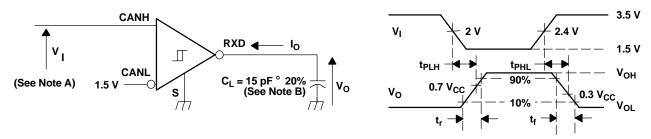


Figure 5. Receiver Voltage and Current Definitions



- A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 125 kHz, 50% duty cycle, $t_r \leq$ 6 ns, $t_l \leq$ 6ns, $Z_O = 50 \Omega$.
- B. C₁ includes instrumentation and fixture capacitance within ±20%.

Figure 6. Receiver Test Circuit and Voltage Waveforms

		. •			
	INPUT		OUTPUT		
V _{CANH}	V _{CANH} V _{CANL}		R		
–11.1 V	–12 V	900 mV	L	V _{OL}	
12 V	11.1 V	900 mV	L		
−6 V	-12 V	6 V	L		
12 V	6 V	6 V	L		
–11.5 V	-12 V	500 mV	Н	V _{OH}	
12 V	11.5 V	500 mV	Н		
–12 V	-6 V	6 V	Н		
6 V	12 V	6 V	Н		
Open	Open	X	Н		

Table 1. Differential Input Voltage Threshold Test



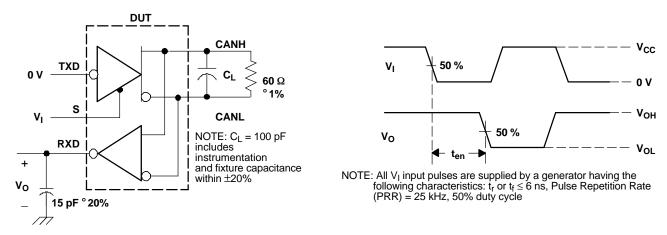
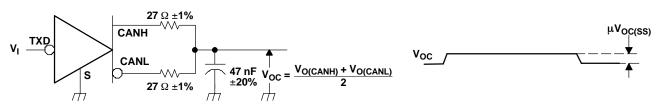
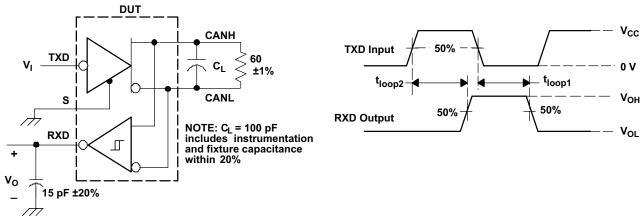


Figure 7. t_{en} Test Circuit and Waveform



NOTE: All V_1 input pulses are from 0 V to V_{CC} and supplied by a generator having the following characteristics: t_r or $t_f \le 6$ ns. Pulse Repetition Rate (PRR) = 125 kHz, 50% duty cycle.

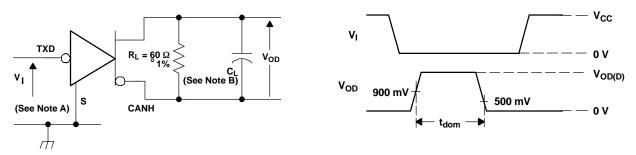
Figure 8. Common Mode Output Voltage Test and Waveforms



A. All V_1 input pulses are from 0 V to V_{CC} and supplied by a generator having the following characteristics: t_r or $t_f \le 6$ ns. Pulse Repetition Rate (PRR) = 125 kHz, 50% duty cycle.

Figure 9. t_(LOOP) Test Circuit and Waveform





- A. All V_I input pulses are from 0 V to V_{CC} and supplied by a generator having the following characteristics: t_r or $t_f \le 6$ ns. Pulse Repetition Rate (PRR) = 500 Hz, 50% duty cycle.
- B. $C_1 = 100 \text{ pF}$ includes instrumentation and fixture capacitance within $\pm 20\%$.

Figure 10. Dominant Time-Out Test Circuit and Waveforms

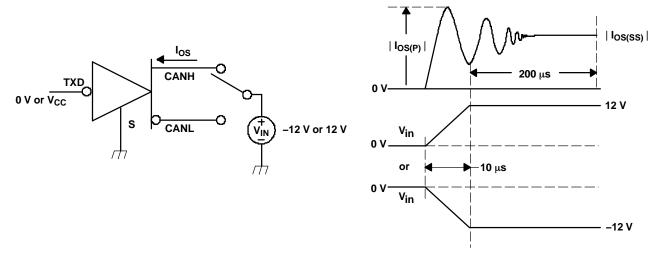


Figure 11. Driver Short-Circuit Current Test and Waveform



DEVICE INFORMATION

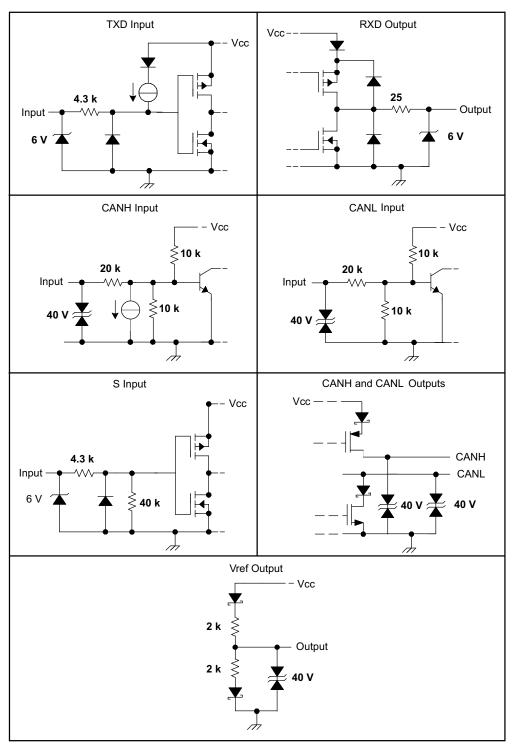
Table 2. Parametric Cross Reference With the TJA1050

TJA1050 ⁽¹⁾	PARAMETER	HVD1050						
TRANSMITTER SECTION								
V _{IH}	High-level input voltage	Recommended V _{IH}						
V _{IL}	Low-level input voltage	Recommended V _{IL}						
I _{IH}	High-level input current	Driver I _{IH}						
I _{IL}	Low-level input current	Driver I _{IL}						
	BUS S	ECTION						
ILI	Power-off bus input current	Receiver I _{I(off)}						
I _{O(SC)}	Short-circuit output current	Driver I _{OS(SS)}						
V _{O(dom)}	Dominant output voltage	Driver V _{O(D)}						
V _{i(dif)(th)}	Differential input voltage	Receiver V _{IT} and recommended V _{ID}						
V _{i(dif)(hys)}	Diffrential input hysteresis	Receiver V _{hys}						
V _{O(reces)}	Recessive output voltage	Driver V _{O(R)}						
V _{O(dif)(bus)}	Differential bus voltage	Driver V _{OD(D)} and V _{OD(R)}						
R _{i(cm)}	CANH, CANL input resistance	Receiver R _{IN}						
R _{i(dif)}	Differential input resistance	Receiver R _{ID}						
R _{i(cm)(m)}	Input resistance matching	Receiver R _{I (m)}						
C _i	Input capacitance to ground	Receiver C _I						
C _{i(dif)}	Differential input capacitance	Receiver C _{ID}						
	RECEIVE	R SECTION						
I _{OH}	High-level output current	Recommended I _{OH}						
I _{OL}	Low-level output current	Recommended I _{OL}						
	Vref PIN	SECTION						
V _{ref}	Reference output voltage	Vo						
	TIMING	SECTION						
t _{d(TXD-BUSon)}	Delay TXD to bus active	Driver t _{PLH}						
t _{d(TXD-BUSoff)}	Delay TXD to bus inactive	Driver t _{PHL}						
t _{d(BUSon-RXD)}	Delay bus active to RXD	Receiver t _{PHL}						
t _{d(BUSoff-RXD)}	Delay bus inactive to RXD	Receiver t _{PLH}						
	$t_{d(TXD-BUSon)} + t_{d(BUSon-RXD)}$	Device t _{LOOP1}						
	t _d (TXD-BUSoff) + t _d (BUSoff-RXD)	Device t _{LOOP2}						
t _{dom(TXD)}	Dominant time out	Driver t _(dom)						
	S PIN S	ECTION						
V _{IH}	High-level input voltage	Recommended V _{IH}						
V _{IL}	Low-level input voltage	Recommended V _{IL}						
I _{IH}	High-level input current	I _{IH}						
I _{IL}	Low-level input current	I _{IL}						

⁽¹⁾ From TJA1050 Product Specification, Philips Semiconductors, 2002 May 16.



Equivalent Input and Output Schematic Diagrams





TYPICAL CHARACTERISTICS

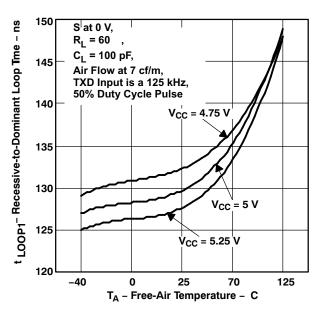


Figure 12. Recessive-to-Dominant Loop Time vs. Free-Air Temperature (across V_{CC})

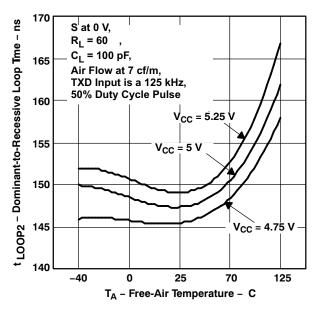


Figure 13. Dominant-to-Recessive Loop Time vs Free-Air Temperature (across V_{CC})



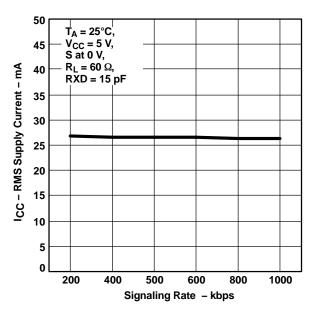


Figure 14. Supply Current (RMS) vs Signaling Rate

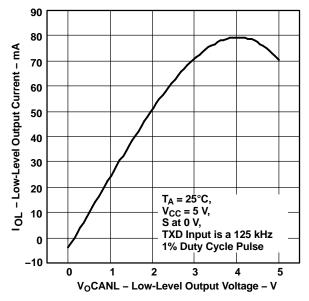


Figure 15. Driver Low-Level Output Voltage vs. Low-Level Output Current



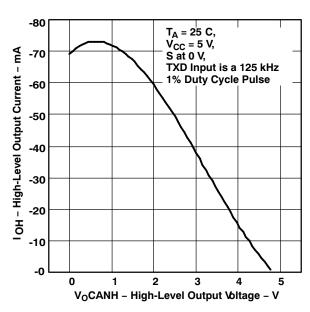


Figure 16. Driver High-Level Output Voltage vs High-Level Output Current

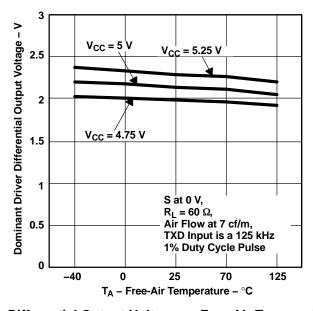


Figure 17. Driver Differential Output Voltage vs Free-Air Temperature (across V_{CC})



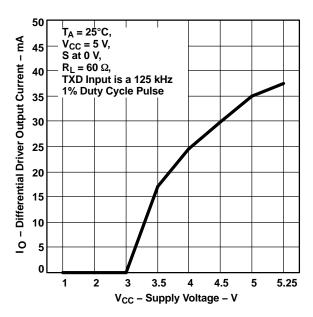


Figure 18. Driver Output Current vs. Supply Voltage

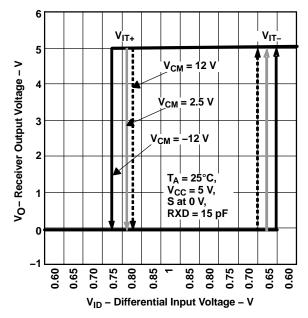


Figure 19. Typical Driver Output Waveform



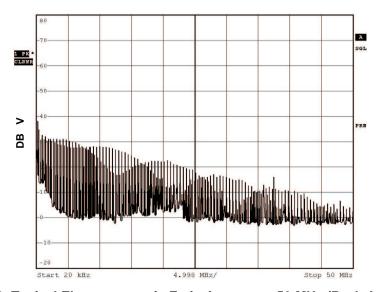


Figure 20. Typical Electromagnetic Emissions up to 50 MHz (Peak Amplitude)

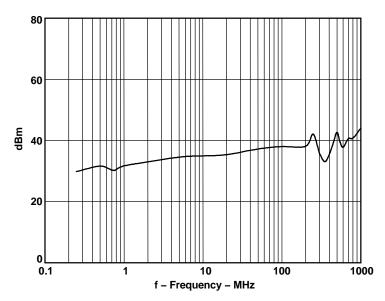


Figure 21. Typical Electromagnetic Immunity Performance





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PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	e Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
SN65HVD1050D	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD1050DG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD1050DR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65HVD1050DRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

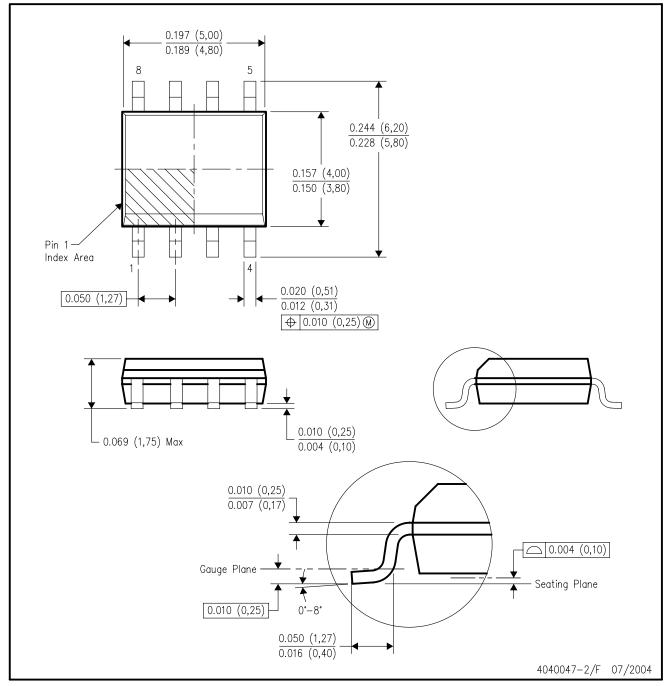
(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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D (R-PDSO-G8)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-012 variation AA.



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